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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4F
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	CANbus, FlexIO, I ² C, LINbus, SPI, UART/USART
Peripherals	POR, PWM, WDT
Number of I/O	89
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 16x12b SAR; D/A1x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/fs32k142hft0mlt

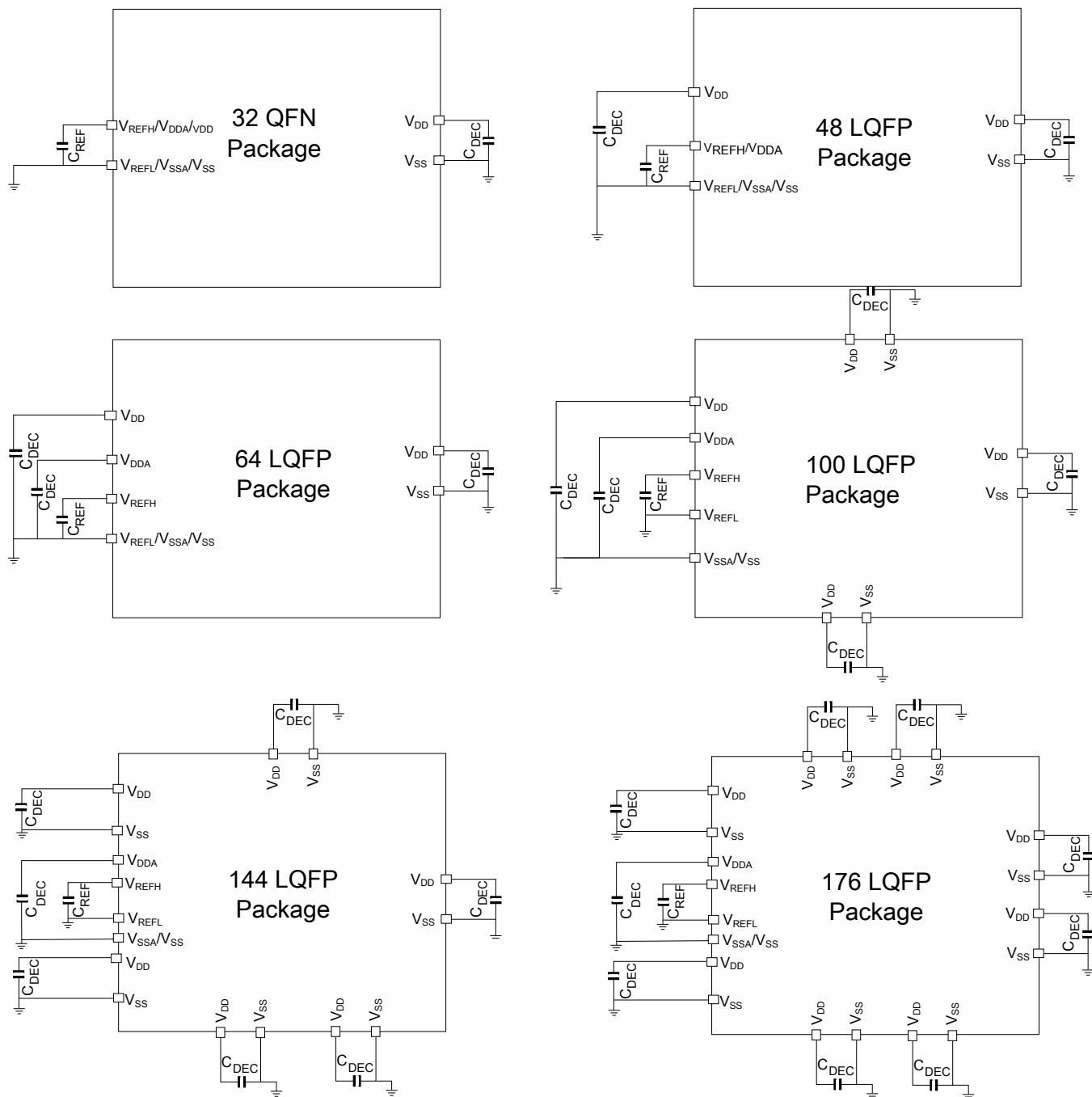
- Communications interfaces
 - Up to three Low Power Universal Asynchronous Receiver/Transmitter (LPUART/LIN) modules with DMA support and low power availability
 - Up to three Low Power Serial Peripheral Interface (LPSPI) modules with DMA support and low power availability
 - Up to two Low Power Inter-Integrated Circuit (LPI2C) modules with DMA support and low power availability
 - Up to three FlexCAN modules (with optional CAN-FD support)
 - FlexIO module for emulation of communication protocols and peripherals (UART, I2C, SPI, I2S, LIN, PWM, etc).
 - Up to one 10/100Mbps Ethernet with IEEE1588 support and two Synchronous Audio Interface (SAI) modules.
- Safety and Security
 - Cryptographic Services Engine (CSEc) implements a comprehensive set of cryptographic functions as described in the SHE (Secure Hardware Extension) Functional Specification. Note: CSEc (Security) or EEPROM writes/erase will trigger error flags in HSRUN mode (112 MHz) because this use case is not allowed to execute simultaneously. The device will need to switch to RUN mode (80 MHz) to execute CSEc (Security) or EEPROM writes/erase.
 - 128-bit Unique Identification (ID) number
 - Error-Correcting Code (ECC) on flash and SRAM memories
 - System Memory Protection Unit (System MPU)
 - Cyclic Redundancy Check (CRC) module
 - Internal watchdog (WDOG)
 - External Watchdog monitor (EWM) module
- Timing and control
 - Up to eight independent 16-bit FlexTimers (FTM) modules, offering up to 64 standard channels (IC/OC/PWM)
 - One 16-bit Low Power Timer (LPTMR) with flexible wake up control
 - Two Programmable Delay Blocks (PDB) with flexible trigger system
 - One 32-bit Low Power Interrupt Timer (LPIT) with 4 channels
 - 32-bit Real Time Counter (RTC)
- Package
 - 32-pin QFN, 48-pin LQFP, 64-pin LQFP, 100-pin LQFP, 100-pin MAPBGA, 144-pin LQFP, 176-pin LQFP package options
- 16 channel DMA with up to 63 request sources using DMAMUX

3 Ordering information

3.1 Selecting orderable part number

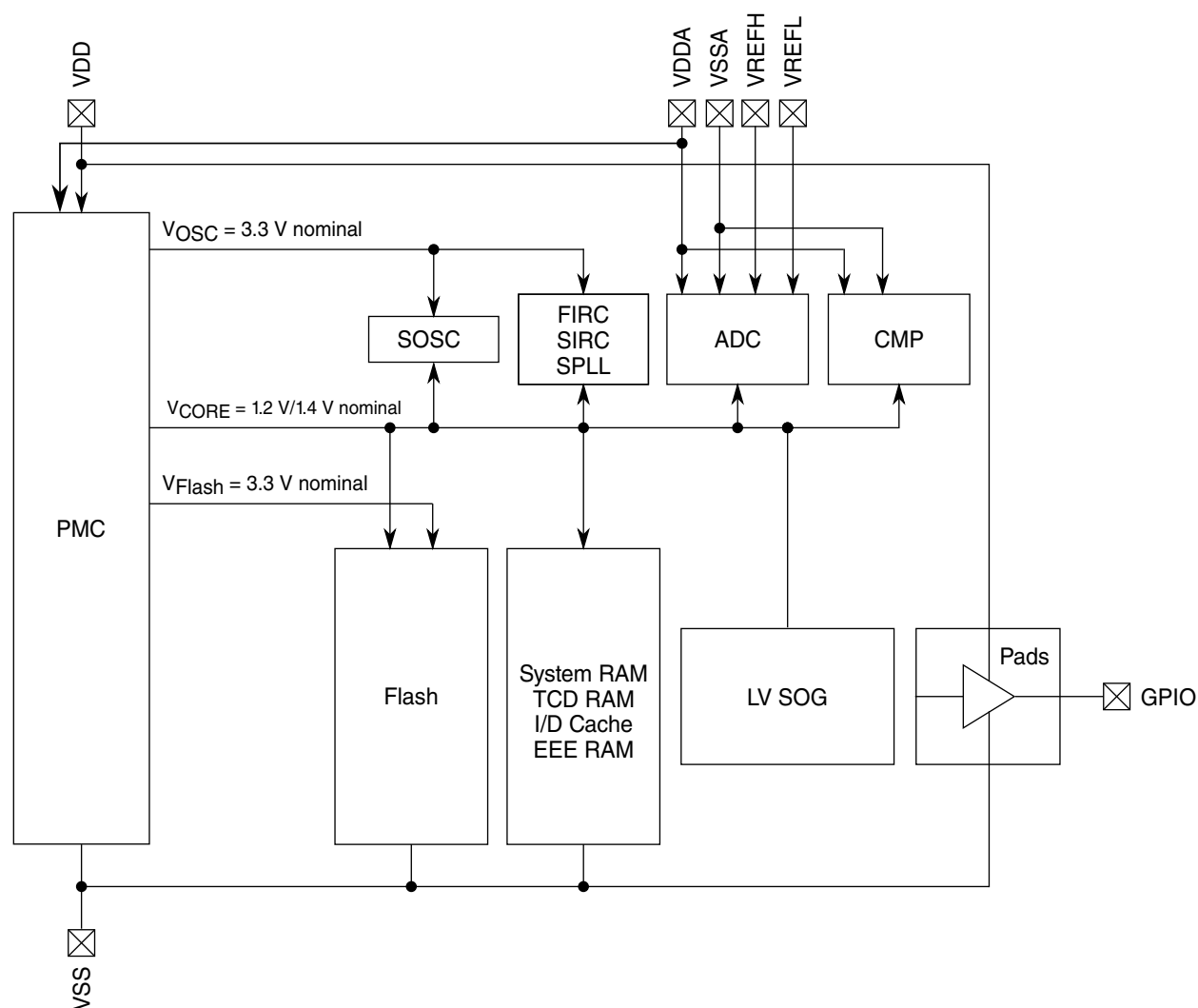
Not all part number combinations are available. See the attachment *S32K1xx_Orderable_Part_Number_List.xlsx* attached with the Datasheet for a list of standard orderable part numbers.

4.4 Power and ground pins



NOTE: V_{DD} and V_{DDA} must be shorted to a common source on PCB

Figure 5. Pinout decoupling



*Note: VSSA and VSS are shorted at package level

Figure 6. Power diagram

4.5 LVR, LVD and POR operating requirements

Table 5. V_{DD} supply LVR, LVD and POR operating requirements

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{POR}	Rising and falling V_{DD} POR detect voltage	1.1	1.6	2.0	V	
V_{LVR}	LVR falling threshold (RUN, HSRUN, and STOP modes)	2.50	2.58	2.7	V	
V_{LVR_HYST}	LVR hysteresis	—	45	—	mV	1
V_{LVR_LP}	LVR falling threshold (VLPS/VLPR modes)	1.97	2.22	2.44	V	
V_{LVD}	Falling low-voltage detect threshold	2.8	2.875	3	V	
V_{LVD_HYST}	LVD hysteresis	—	50	—	mV	1

Table continues on the next page...

Table 5. V_{DD} supply LVR, LVD and POR operating requirements (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{LVW}	Falling low-voltage warning threshold	4.19	4.305	4.5	V	
V_{LVW_HYST}	LVW hysteresis	—	75	—	mV	1
V_{BG}	Bandgap voltage reference	0.97	1.00	1.03	V	

1. Rising threshold is the sum of falling threshold and hysteresis voltage.

4.6 Power mode transition operating behaviors

All specifications in the following table assume this clock configuration:

- RUN Mode:
 - Clock source: FIRC
 - SYS_CLK/CORE_CLK = 48 MHz
 - BUS_CLK = 48 MHz
 - FLASH_CLK = 24 MHz
- HSRUN Mode:
 - Clock source: SPL
 - SYS_CLK/CORE_CLK = 112 MHz
 - BUS_CLK = 56 MHz
 - FLASH_CLK = 28 MHz
- VLPR Mode:
 - Clock source: SIRC
 - SYS_CLK/CORE_CLK = 4 MHz
 - BUS_CLK = 4 MHz
 - FLASH_CLK = 1 MHz
- STOP1/STOP2 Mode:
 - Clock source: FIRC
 - SYS_CLK/CORE_CLK = 48 MHz
 - BUS_CLK = 48 MHz
 - FLASH_CLK = 24 MHz
- VLPS Mode: All clock sources disabled ¹

Table 6. Power mode transition operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit
t_{POR}	After a POR event, amount of time from the point V_{DD} reaches 2.7 V to execution of the first instruction across the operating temperature range of the chip.	—	325	—	μ s

Table continues on the next page...

1.

- For S32K11x – FIRC/SOSC
- For S32K14x – FIRC/SOSC/SPLL

Table 7. Power consumption (Typicals unless stated otherwise) ¹

Chip/Device	Ambient Temperature (°C)		VLPS (μA) ²		VLPR (mA)			STOP1 (mA)	STOP2 (mA)	RUN@48 MHz (mA)		RUN@64 MHz (mA)		RUN@80 MHz (mA)		HSRUN@112 MHz (mA) ³		IDD/MHz (μA/MHz) ⁴
			Peripherals disabled ⁵	Peripherals enabled	Peripherals disabled ⁶	Peripherals enabled use case 1 ⁶	Peripherals enabled use case 2 ⁷			Peripherals disabled	Peripherals enabled	Peripherals disabled	Peripherals enabled	Peripherals disabled	Peripherals enabled	Peripherals disabled	Peripherals enabled	
S32K116	25	Typ	26	40	1.05	1.07	TBD	6.3	7.2	11.8	20.3	NA						245
	85	Typ	76	93	1.1	1.11	TBD	6.6	7.5	12	20.6							251
		Max	287	300	1.39	1.4	NA	8	8.9	13.4	22.1							279
	105	Typ	139	164	1.15	1.16	TBD	6.8	7.7	12.3	20.8							255
		Max	590	603	1.68	1.69	NA	9.2	10.1	14.5	23.1							302
	125	Typ	NA	NA	NA	NA	TBD	NA	NA	NA	NA							NA
		Max	891	904	2.02	2.04	NA	10.4	11.3	15.6	24.1							325
S32K118	25	Typ	26	38	1.9	2.5	TBD	7	12	TBD	TBD	NA						TBD
	105	Typ	TBD	TBD	TBD	TBD	TBD	TBD	TBD	TBD	TBD							TBD
		Max	TBD	TBD	TBD	TBD	TBD	TBD	TBD	TBD	TBD							TBD
	125	Max	TBD	TBD	TBD	TBD	TBD	TBD	TBD	TBD	TBD							TBD
											42							
S32K142	25	Typ	29	40	1.17	1.21	2.19	6.4	7.4	17.3	24.6	24.5	31.3	28.8	37.5	40.5	52.2	360
	85	Typ	128	137	1.48	1.51	2.31	7	8	17.6	24.9	25	31.6	29.1	37.7	41.1	52.5	364
		Max	335	360	1.87	1.89	NA	8.6	9.4	22	28.2	26.9	33.5	32	40	44	55.6	400
	105	Typ	240	257	1.58	1.61	2.44	7.6	8.3	18.3	25.7	25.5	31.9	29.8	38	41.5	53.1	373
		Max	740	791	2.32	2.34	NA	9.9	10.9	23.1	30.2	27.8	35.3	33.8	40.7	44.9	57.4	423
	125	Typ	NA	NA	NA	NA	2.84	NA	NA	NA	NA	NA	NA	NA	NA	NA	NA	NA

Table continues on the next page...

Table 8. VLPS additional use-case power consumption at typical conditions

Use-case	Description	Temp.	Device						Unit
			S32K116	S32K118	S32K142	S32K144	S32K146	S32K148	
VLPS and RTC	Clock source: LPO or RTC_CLKIN	25	TBD	TBD	30	30	30	40	μA
		85	TBD	TBD	110	170	180	240	μA
		105	TBD	TBD	230	330	350	490	μA
		125	TBD	TBD	570	680	810	1250	μA
VLPS and LPUART TX/RX	- Clock source: SIRC - Transmitting or receiving continuously using DMA - Baudrate: 19.2 kbps	25	TBD	TBD	230	230	250	250	μA
		85	TBD	TBD	320	400	410	490	μA
		105	TBD	TBD	490	550	600	850	μA
		125	TBD	TBD	890	1070	1250	1960	μA
VLPS and LPUART wake-up	- Clock source: SIRC - Wake-up address feature enabled - Baudrate: 19.2 kbps	25	TBD	TBD	100	100	110	110	μA
		85	TBD	TBD	170	240	280	350	μA
		105	TBD	TBD	260	400	480	600	μA
		125	TBD	TBD	530	580	1000	1280	μA
VLPS and LPI2C master	- Clock Source: SIRC - Transmit/receive using DMA - Baudrate: 100 kHz	25	TBD	TBD	670	690	820	900	μA
		85	TBD	TBD	880	960	1220	1370	μA
		105	TBD	TBD	1080	1250	1660	2060	μA
		125	TBD	TBD	1970	1980	2860	3690	μA
VLPS and LPI2C slave wake-up	- Clock source: SIRC - Wake-up address feature enabled - Baudrate: 100 kHz	25	TBD	TBD	250	250	270	280	μA
		85	TBD	TBD	340	340	410	510	μA
		105	TBD	TBD	430	430	610	810	μA
		125	TBD	TBD	740	760	1170	1540	μA
VLPS and LPSPi master	- Clock source: SIRC - Transmit/receive using DMA - Baudrate: 500 kHz	25	TBD	TBD	2.99	3.19	3.75	4.11	mA
		85	TBD	TBD	3.26	3.7	4.35	4.93	mA
		105	TBD	TBD	3.5	4.2	4.93	5.74	mA
		125	TBD	TBD	3.93	4.63	5.97	7.38	mA
VLPS and LPiT	- Clock source: SIRC 1 channel enable - Mode: 32-bit periodic counter	25	TBD	TBD	100	100	120	130	μA
		85	TBD	TBD	190	250	260	320	μA
		105	TBD	TBD	310	410	440	570	μA
		125	TBD	TBD	640	750	910	1280	μA

5.3 DC electrical specifications at 3.3 V Range

NOTE

For details on the pad types defined in [Table 11](#) and [Table 12](#), see Reference Manual section *IO Signal Table* and IO Signal Description Input Multiplexing sheet(s) attached with Reference Manual.

Table 11. DC electrical specifications at 3.3 V Range

Symbol	Parameter	Value			Unit	Notes
		Min.	Typ.	Max.		
V_{DD}	I/O Supply Voltage	2.7	3.3	4	V	1
V_{ih}	Input Buffer High Voltage	$0.7 \times V_{DD}$	—	$V_{DD} + 0.3$	V	2
V_{il}	Input Buffer Low Voltage	$V_{SS} - 0.3$	—	$0.3 \times V_{DD}$	V	3
V_{hys}	Input Buffer Hysteresis	$0.06 \times V_{DD}$	—	—	V	
$I_{oh_{GPIO}}$ $I_{oh_{GPIO-HD_DSE_0}}$	I/O current source capability measured when pad $V_{oh} = (V_{DD} - 0.8 \text{ V})$	3.5	—	—	mA	
$I_{ol_{GPIO}}$ $I_{ol_{GPIO-HD_DSE_0}}$	I/O current sink capability measured when pad $V_{ol} = 0.8 \text{ V}$	3	—	—	mA	
$I_{oh_{GPIO-HD_DSE_1}}$	I/O current source capability measured when pad $V_{oh} = (V_{DD} - 0.8 \text{ V})$	14	—	—	mA	4
$I_{ol_{GPIO-HD_DSE_1}}$	I/O current sink capability measured when pad $V_{ol} = 0.8 \text{ V}$	12	—	—	mA	4
$I_{oh_{GPIO-FAST_DSE_0}}$	I/O current sink capability measured when pad $V_{oh}=V_{DD}-0.8 \text{ V}$	9.5	—	—	mA	5
$I_{ol_{GPIO-FAST_DSE_0}}$	I/O current sink capability measured when pad $V_{ol} = 0.8 \text{ V}$	10	—	—	mA	5
$I_{oh_{GPIO-FAST_DSE_1}}$	I/O current sink capability measured when pad $V_{oh}=V_{DD}-0.8 \text{ V}$	16	—	—	mA	5
$I_{ol_{GPIO-FAST_DSE_1}}$	I/O current sink capability measured when pad $V_{ol} = 0.8 \text{ V}$	15.5	—	—	mA	5
IOHT	Output high current total for all ports	—	—	100	mA	
IIN	Input leakage current (per pin) for full temperature range at $V_{DD} = 3.3 \text{ V}$					6
	All pins other than high drive port pins		0.005	0.5	μA	
	High drive port pins ⁷		0.010	0.5	μA	
R_{PU}	Internal pullup resistors	20		60	$k\Omega$	8
R_{PD}	Internal pulldown resistors	20		60	$k\Omega$	9

1. S32K148 will operate from 2.7 V when executing from internal FIRC. When the PLL is engaged S32K148 is guaranteed to operate from 2.97 V. All other S32K family devices operate from 2.7 V in all modes.
2. For reset pads, same V_{ih} levels are applicable
3. For reset pads, same V_{il} levels are applicable
4. The value given is measured at high drive strength mode. For value at low drive strength mode see the $I_{oh_Standard}$ value given above.
5. For reference only. Run simulations with the IBIS model and custom board for accurate results.

5. Several I/O have both high drive and normal drive capability selected by the associated Portx_PCRn[DSE] control bit. All other GPIOs are normal drive only. For details refer to *SK3K144_IO_Signal_Description_Input_Multiplexing.xlsx* attached with the *Reference Manual*.
6. Measured at input $V = V_{SS}$
7. Measured at input $V = V_{DD}$

5.5 AC electrical specifications at 3.3 V range

Table 13. AC electrical specifications at 3.3 V Range

Symbol	DSE	Rise time (nS) ¹		Fall time (nS) ¹		Capacitance (pF) ²
		Min.	Max.	Min.	Max.	
tRF _{GPIO}	NA	3.2	14.5	3.4	15.7	25
		5.7	23.7	6.0	26.2	50
		20.0	80.0	20.8	88.4	200
tRF _{GPIO-HD}	0	3.2	14.5	3.4	15.7	25
		5.7	23.7	6.0	26.2	50
		20.0	80.0	20.8	88.4	200
	1	1.5	5.8	1.7	6.1	25
		2.4	8.0	2.6	8.3	50
		6.3	22.0	6.0	23.8	200
tRF _{GPIO-FAST}	0	0.6	2.8	0.5	2.8	25
		3.0	7.1	2.6	7.5	50
		12.0	27.0	10.3	26.8	200
	1	0.4	1.3	0.38	1.3	25
		1.5	3.8	1.4	3.9	50
		7.4	14.9	7.0	15.3	200

1. For reference only. Run simulations with the IBIS model and your custom board for accurate results.
2. Maximum capacitances supported on Standard IOs. However interface or protocol specific specifications might be different, for example for ENET, QSPI etc. . For protocol specific AC specifications, see respective sections.

5.6 AC electrical specifications at 5 V range

Table 14. AC electrical specifications at 5 V Range

Symbol	DSE	Rise time (nS) ¹		Fall time (nS) ¹		Capacitance (pF) ²
		Min.	Max .	Min.	Max.	
tRF _{GPIO}	NA	2.8	9.4	2.9	10.7	25
		5.0	15.7	5.1	17.4	50
		17.3	54.8	17.6	59.7	200
tRF _{GPIO-HD}	0	2.8	9.4	2.9	10.7	25
		5.0	15.7	5.1	17.4	50

Table continues on the next page...

Table 16. Device clock specifications 1 (continued)

Symbol	Description	Min.	Max.	Unit
f _{FLASH}	Flash clock	—	24	MHz
Normal run mode (S32K14x series) ³				
f _{SYS}	System and core clock	—	80	MHz
f _{BUS}	Bus clock	—	40 ⁴	MHz
f _{FLASH}	Flash clock	—	26.67	MHz
VLPR mode ⁵				
f _{SYS}	System and core clock	—	4	MHz
f _{BUS}	Bus clock	—	4	MHz
f _{FLASH}	Flash clock	—	1	MHz
f _{ERCLK}	External reference clock	—	16	MHz

1. Refer to the section [Feature comparison](#) for the availability of modes and other specifications.
2. Only available on some devices. See section [Feature comparison](#).
3. With SPLP as system clock source.
4. 48 MHz when f_{SYS} is 48 MHz
5. The frequency limitations in VLPR mode here override any frequency specification listed in the timing specification for any other module.

6 Peripheral operating requirements and behaviors

6.1 System modules

There are no electrical specifications necessary for the device's system modules.

6.2 Clock interface modules

6.2.1 External System Oscillator electrical specifications

Table 23. Flash command timing specifications for S32K14x (continued)

Symbol	Description ¹		S32K142		S32K144		S32K146		S32K148		Unit Notes	
			Typ	Max	Typ	Max	Typ	Max	Typ	Max		
	setting (32-bit write complete, ready for next 32-bit write)	Last (Nth) 32-bit write (time for write only, not cleanup)	200	550	200	550	200	550	200	550		
$t_{\text{quickwrClnup}}$	Quick Write Cleanup execution time	—	—	(# of Quick Writes) * 2.0	—	(# of Quick Writes) * 2.0	—	(# of Quick Writes) * 2.0	—	(# of Quick Writes) * 2.0	ms	7

1. All command times assumes 25 MHz or greater flash clock frequency (for synchronization time between internal/external clocks).
2. Maximum times for erase parameters based on expectations at cycling end-of-life.
3. For all EEPROM Emulation terms, the specified timing shown assumes previous record cleanup has occurred. This may be verified by executing FCCOB Command 0x77, and checking FCCOB number 5 contents show 0x00 - No EEPROM issues detected.
4. 1st time EERAM writes after a Reset or SETRAM may incur additional overhead for EEE cleanup, resulting in up to 2x the times shown.
5. Only after the Nth write completes will any data be valid. Emulated EEPROM record scheme cleanup overhead may occur after this point even after a brownout or reset. If power on reset occurs before the Nth write completes, the last valid record set will still be valid and the new records will be discarded.
6. Quick Write times may take up to 550 μ s, as additional cleanup may occur when crossing sector boundaries.
7. Time for emulated EEPROM record scheme overhead cleanup. Automatically done after last (Nth) write completes, assuming still powered. Or via SETRAM cleanup execution command is requested at a later point.

Table 24. Flash command timing specifications for S32K11x

Symbol	Description ¹		S32K116		S32K118		Unit Notes	
			Typ	Max	Typ	Max		
t_{rd1blk}	Read 1 Block execution time	32 KB flash	—	0.36	—	0.36	ms	
		64 KB flash	—	—	—	—		
		128 KB flash	—	1.2	—	—		
		256 KB flash	—	—	—	2		
		512 KB flash	—	—	—	—		
t_{rd1sec}	Read 1 Section execution time	2 KB flash	—	75	—	75	μ s	
		4 KB flash	—	100	—	100		
t_{pgmchk}	Program Check execution time	—	—	100	—	100	μ s	
t_{pgm8}	Program Phrase execution time	—	90	225	90	225	μ s	
t_{ersblk}	Erase Flash Block execution time	32 KB flash	15	300	15	300	ms	2
		64 KB flash	—	—	—	—		
		128 KB flash	120	1100	—	—		
		256 KB flash	—	—	250	2125		
		512 KB flash	—	—	—	—		

Table continues on the next page...

Table 24. Flash command timing specifications for S32K11x (continued)

Symbol	Description ¹		S32K116		S32K118		Unit		Notes
			Typ	Max	Typ	Max			
t _{eewr32b}	32-bit write to FlexRAM execution time	32 KB EEPROM backup	630	2000	630	2000	μs		3·4
		48 KB EEPROM backup	—	—	—	—			
		64 KB EEPROM backup	—	—	—	—			
t _{quickwr}	32-bit Quick Write execution time: Time from CCIF clearing (start the write) until CCIF setting (32-bit write complete, ready for next 32-bit write)	1st 32-bit write	200	550	200	550	μs		4·5·6
		2nd through Next to Last (Nth-1) 32-bit write	150	550	150	550			
		Last (Nth) 32-bit write (time for write only, not cleanup)	200	550	200	550			
t _{quickwrClnup}	Quick Write Cleanup execution time	—	—	(# of Quick Writes) * 2.0	—	(# of Quick Writes) * 2.0	ms		7

1. All command times assume 25 MHz or greater flash clock frequency (for synchronization time between internal/external clocks).
2. Maximum times for erase parameters based on expectations at cycling end-of-life.
3. For all EEPROM Emulation terms, the specified timing shown assumes previous record cleanup has occurred. This may be verified by executing FCCOB Command 0x77, and checking FCCOB number 5 contents show 0x00 - No EEPROM issues detected.
4. 1st time EERAM writes after a Reset or SETRAM may incur additional overhead for EEE cleanup, resulting in up to 2x the times shown.
5. Only after the Nth write completes will any data be valid. Emulated EEPROM record scheme cleanup overhead may occur after this point even after a brownout or reset. If power on reset occurs before the Nth write completes, the last valid record set will still be valid and the new records will be discarded.
6. Quick Write times may take up to 550 μs, as additional cleanup may occur when crossing sector boundaries.
7. Time for emulated EEPROM record scheme overhead cleanup. Automatically done after last (Nth) write completes, assuming still powered. Or via SETRAM cleanup execution command is requested at a later point.

NOTE

Under certain circumstances FlexMEM maximum times may be exceeded. In this case the user or application may wait, or assert reset to the FTFC macro to stop the operation.

6.3.1.2 Reliability specifications

Table 25. NVM reliability specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
When using as Program and Data Flash						
t _{nvmretp1k}	Data retention after up to 1 K cycles	20	—	—	years	1
η _{nvmcycp}	Cycling endurance	1 K	—	—	cycles	2, 3

Table continues on the next page...

Table 26. QuadSPI electrical specifications

FLASH PORT	Sym	Unit	FLASH A												FLASH B			
			RUN ¹						HSRUN ¹						RUN/HSRUN ²			
QuadSPI Mode			SDR						SDR						SDR		DDR ³	
			Internal Sampling		Internal DQS				Internal Sampling		Internal DQS				Internal Sampling		External DQS	
			N1		PAD Loopback		Internal Loopback		N1		PAD Loopback		Internal Loopback		N1		External DQS	
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max
Register Settings																		
MCR[DDR_EN]		-	0		0		0		0		0		0		0		1	
MCR[DQS_EN]		-	0		1		1		0		1		1		0		1	
MCR[SCLKCFG[0]]		-	-		1		0		-		1		0		-		-	
MCR[SCLKCFG[1]]		-	-		1		0		-		1		0		-		-	
MCR[SCLKCFG[2]]		-	-		-		-		-		-		-		-		0	
MCR[SCLKCFG[3]]		-	-		-		-		-		-		-		-		0	
MCR[SCLKCFG[5]]		-	0		0		0		0		0		0		0		1	
SMPR[FSPHS]		-	0		1		0		0		1		0		0		0	
SMPR[FSDLY]		-	0		0		0		0		0		0		0		0	
SOCCR [SOCCFG[7:0]]			-		0		23		-		0		30		-		-	
SOCCR[SOCCFG[15:8]]		-	-		-		-		-		-		-		-		30	
FLSHCR[TDH]		-	0x00		0x00		0x00		0x00		0x00		0x00		0x00		0x01	
Timing Parameters																		
SCK Clock Frequency	f _{SCK}	MHz	-	38	-	64	-	48	-	40	-	80	-	50	-	20	-	20 ⁴
SCK Clock Period	t _{SCK}	ns	1/f _{SCK}	-	1/f _{SCK}	-	1/f _{SCK}	-	1/f _{SCK}	-	1/f _{SCK}	-	1/f _{SCK}	-	50.0	-	50.0 ⁴	-

Table continues on the next page...

6.4.2 CMP with 8-bit DAC electrical specifications

Table 31. Comparator with 8-bit DAC electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit
I _{DDHS}	Supply current, High-speed mode ¹				μA
	-40 - 125 °C	—	230	300	
I _{DDL}	Supply current, Low-speed mode ¹				μA
	-40 - 105 °C	—	6	11	
	-40 - 125 °C		6	13	
V _{AIN}	Analog input voltage	0	0 - V _{DDA}	V _{DDA}	V
V _{AIO}	Analog input offset voltage, High-speed mode				mV
	-40 - 125 °C	-25	±1	25	
V _{AIO}	Analog input offset voltage, Low-speed mode				mV
	-40 - 125 °C	-40	±4	40	
t _{DHSB}	Propagation delay, High-speed mode ²				ns
	-40 - 105 °C	—	35	200	
	-40 - 125 °C		35	300	
t _{DL}	Propagation delay, Low-speed mode ²				μs
	-40 - 105 °C	—	0.5	2	
	-40 - 125 °C	—	0.5	3	
t _{DH}	Propagation delay, High-speed mode ³				ns
	-40 - 105 °C	—	70	400	
	-40 - 125 °C	—	70	500	
t _{DL}	Propagation delay, Low-speed mode ³				μs
	-40 - 105 °C	—	1	5	
	-40 - 125 °C	—	1	5	
t _{IDH}	Initialization delay, High-speed mode ⁴				μs
	-40 - 125 °C	—	1.5	3	
t _{IDL}	Initialization delay, Low-speed mode ⁴				μs
	-40 - 125 °C	—	10	30	
V _{HYST0}	Analog comparator hysteresis, Hyst0				mV
	-40 - 125 °C	—	0	—	
V _{HYST1}	Analog comparator hysteresis, Hyst1, High-speed mode				mV
	-40 - 125 °C	—	19	66	
	Analog comparator hysteresis, Hyst1, Low-speed mode				
	-40 - 125 °C	—	15	40	
V _{HYST2}	Analog comparator hysteresis, Hyst2, High-speed mode				mV
	-40 - 125 °C	—	34	133	

Table continues on the next page...

Table 32. LPSPI electrical specifications¹

Num	Symbol	Description	Conditions	Run Mode ²				HSRUN Mode ²				VLPR Mode				Unit
				5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		
				Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
	f _{periph} ^{3, 4}	Peripheral Frequency	Slave	-	40	-	40	-	56	-	56	-	4	-	4	MHz
			Master	-	40	-	40	-	56	-	56	-	4	-	4	
			Master Loopback ⁵	-	40	-	48	-	48	-	48	-	4	-	4	
			Master Loopback(slow) ⁶	-	48	-	48	-	48	-	48	-	4	-	4	
1	f _{op}	Frequency of operation	Slave	-	10	-	10	-	14	-	14 ⁷	-	2	-	2	MHz
			Master	-	10	-	10	-	14	-	14 ⁷	-	2	-	2	
			Master Loopback ⁵	-	20	-	12	-	24	-	12	-	2	-	2	
			Master Loopback(slow) ⁶	-	12	-	12	-	12	-	12	-	2	-	2	
2	t _{SPSCK}	SPSCK period	Slave	100	-	100	-	72	-	72	-	500	-	500	-	ns
			Master	100	-	100	-	72	-	72	-	500	-	500	-	
			Master Loopback ⁵	50	-	83	-	42	-	83	-	500	-	500	-	
			Master Loopback(slow) ⁶	83	-	83	-	83	-	83	-	500	-	500	-	
3	t _{Lead} ⁸	Enable lead time (PCS to SPSCK delay)	Slave	-	-	-	-	-	-	-	-	-	-	-	-	ns
			Master	(PCSSCK+1)*t _{periph} -25	-	(PCSSCK+1)*t _{periph} -25	-	(PCSSCK+1)*t _{periph} -25	-	(PCSSCK+1)*t _{periph} -25	(PCSSCK+1)*t _{periph} -50	-	(PCSSCK+1)*t _{periph} -50	-		
			Master Loopback ⁵													
			Master Loopback(slow) ⁶													

Table continues on the next page...

Table 32. LPSPI electrical specifications¹ (continued)

Num	Symbol	Description	Conditions	Run Mode ²				HSRUN Mode ²				VLPR Mode				Unit
				5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		
				Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
			Master Loopback(slow) ⁶	-		-		-		-		-		-		

- Trace length should not exceed 11 inches for SCK pad when used in Master loopback mode.
- While transitioning from HSRUN mode to RUN mode, LPSPI output clock should not be more than 14 MHz.
- f_{periph} = LPSPI peripheral clock
- $t_{\text{periph}} = 1/f_{\text{periph}}$
- Master Loopback mode - In this mode LPSPI_SCK clock is delayed for sampling the input data which is enabled by setting LPSPI_CFGR1[SAMPLE] bit as 1. Clock pads used are PTD15 and PTE0. Applicable only for LPSPI0.
- Master Loopback (slow) - In this mode LPSPI_SCK clock is delayed for sampling the input data which is enabled by setting LPSPI_CFGR1[SAMPLE] bit as 1. Clock pad used is PTB2. Applicable only for LPSPI0.
- This is the maximum operating frequency (f_{op}) for LPSPI0 with medium PAD type only. Otherwise, the maximum operating frequency (f_{op}) is 12 Mhz.
- Set the PCSSCK configuration bit as 0, for a minimum of 1 delay cycle of LPSPI baud rate clock, where PCSSCK ranges from 0 to 255.
- Set the SCKPCS configuration bit as 0, for a minimum of 1 delay cycle of LPSPI baud rate clock, where SCKPCS ranges from 0 to 255.
- While selecting odd dividers, ensure Duty Cycle is meeting this parameter.
- Maximum operating frequency (f_{op}) is 12 MHz irrespective of PAD type and LPSPI instance.
- Applicable for LPSPI0 only with medium PAD type, with maximum operating frequency (f_{op}) as 14 MHz.

Table 38. SWD electrical specifications

Symbol	Description	Run Mode				HSRUN Mode				VLPR Mode				Unit
		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
S1	SWD_CLK frequency of operation	-	25	-	25	-	25	-	25	-	10	-	10	MHz
S2	SWD_CLK cycle period	1/S1	-	1/S1	-	1/S1	-	1/S1	-	1/S1	-	1/S1	-	ns
S3	SWD_CLK clock pulse width	S2/2 - 5	S2/2 + 5	S2/2 - 5	S2/2 + 5	S2/2 - 5	S2/2 + 5	S2/2 - 5	S2/2 + 5	S2/2 - 5	S2/2 + 5	S2/2 - 5	S2/2 + 5	ns
S4	SWD_CLK rise and fall times	-	1	-	1	-	1	-	1	-	1	-	1	ns
S9	SWD_DIO input data setup time to SWD_CLK rise	4	-	4	-	4	-	4	-	16	-	16	-	ns
S10	SWD_DIO input data hold time after SWD_CLK rise	3	-	3	-	3	-	3	-	10	-	10	-	ns
S11	SWD_CLK high to SWD_DIO data valid	-	28	-	38	-	28	-	38	-	70	-	77	ns
S12	SWD_CLK high to SWD_DIO high-Z	-	28	-	38	-	28	-	38	-	70	-	77	ns
S13	SWD_CLK high to SWD_DIO data invalid	0	-	0	-	0	-	0	-	0	-	0	-	ns

Table 41. Thermal characteristics for 32-pin QFN and 48/64/100/144/176-pin LQFP package

Rating	Conditions	Symbol	Package	Values						Unit
				S32K116	S32K118	S32K142	S32K144	S32K146	S32K148	
Thermal resistance, Junction to Ambient (Natural Convection) ^{1, 2}	Single layer board (1s)	$R_{\theta JA}$	32	93	NA	NA	NA	NA	NA	°C/W
			48	79	71	NA	NA	NA	NA	
			64	NA	62	61	61	59	NA	
			100	NA	NA	53	52	51	NA	
			144	NA	NA	NA	NA	51	44	
			176	NA	NA	NA	NA	NA	42	
Thermal resistance, Junction to Ambient (Natural Convection) ¹	Two layer board (1s1p)	$R_{\theta JA}$	32	50	NA	NA	NA	NA	NA	
			48	58	50	NA	NA	NA	NA	
			64	NA	46	45	45	44	NA	
			100	NA	NA	42	42	40	NA	
			144	NA	NA	NA	NA	44	37	
			176	NA	NA	NA	NA	NA	36	
Thermal resistance, Junction to Ambient (Natural Convection) ^{1, 2}	Four layer board (2s2p)	$R_{\theta JA}$	32	32	NA	NA	NA	NA	NA	
			48	55	47	NA	NA	NA	NA	
			64	NA	44	43	43	41	NA	
			100	NA	NA	40	40	39	NA	
			144	NA	NA	NA	NA	42	36	
			176	NA	NA	NA	NA	NA	35	
Thermal resistance, Junction to Ambient (@200 ft/min) ^{1, 3}	Single layer board (1s)	$R_{\theta JMA}$	32	77	NA	NA	NA	NA	NA	
			48	66	58	NA	NA	NA	NA	
			64	NA	50	49	49	48	NA	
			100	NA	NA	43	42	41	NA	
			144	NA	NA	NA	NA	42	36	
			176	NA	NA	NA	NA	NA	34	
Thermal resistance, Junction to Ambient (@200 ft/min) ¹	Two layer board (1s1p)	$R_{\theta JMA}$	32	43	NA	NA	NA	NA	NA	
			48	51	43	NA	NA	NA	NA	
			64	NA	39	38	38	37	NA	
			100	NA	NA	35	35	34	NA	

Table continues on the next page...

Table 41. Thermal characteristics for 32-pin QFN and 48/64/100/144/176-pin LQFP package (continued)

Rating	Conditions	Symbol	Package	Values						Unit
				S32K116	S32K118	S32K142	S32K144	S32K146	S32K148	
Thermal resistance, Junction to Package Top ⁷	Natural Convection	ψ_{JT}	32	1	NA	NA	NA	NA	NA	
			48	4	2	NA	NA	NA	NA	
			64	NA	2	2	2	2	NA	
			100	NA	NA	2	2	2	NA	
			144	NA	NA	NA	NA	2	1	
			176	NA	NA	NA	NA	NA	1	

1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per JEDEC JESD51-2 with natural convection for horizontally oriented board. Board meets JESD51-9 specification for 1s or 2s2p board, respectively.
3. Per JEDEC JESD51-6 with forced convection for horizontally oriented board. Board meets JESD51-9 specification for 1s or 2s2p board, respectively.
4. Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
6. Thermal resistance between the die and the solder pad on the bottom of the package. Interface resistance is ignored.
7. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written as Psi-JT.

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